

CD4009M/CD4009C Hex Buffers (Inverting) CD4010M/CD4010C Hex Buffers (Non-Inverting)

General Description

These hex buffers are monolithic complementary MOS (CMOS) integrated circuits. The N- and P-channel enhancement mode transistors provide a symmetrical circuit with output swings essentially equal to the supply voltage. This results in high noise immunity over a wide supply voltage range. No DC power other than that caused by leakage current is consumed during static conditions. All inputs are protected against static discharge. These gates may be used as hex buffers, CMOS to DTL or TTL interface or as CMOS current drivers. Conversion ranges are from 3V to 15V providing $V_{CC} \leq V_{DD}$.

Features

- Wide supply voltage range
- Low power

3.0V to 15V 100 nW (typ.)

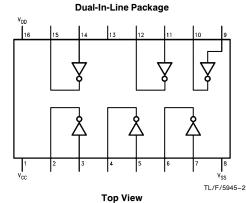
February 1988

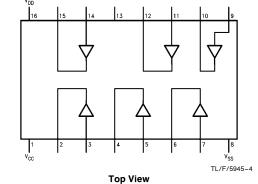
- High noise immunity
 - 0.45 V_{DD} (typ.)
- High current sinking capability
- 8 mA (min.) at $V_O = 0.5V$ and $V_{DD} = 10V$

Applications

- Automotive
- Data terminals
- Instrumentation ■ Medical electronics
- Alarm system
- Industrial controls
- Remote metering
- Computers

Schematic and Connection Diagrams

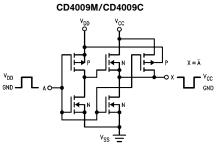


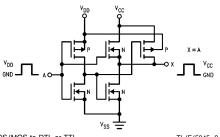


CD4010M/CD4010C

Dual-In-Line Package

Order Number CD4009 or CD4010





Hex COS/MOS to DTL or TTL converter (non-inverting).

Connect V_{CC} to DTL or TTL supply. Connect V_{DD} to COS/MOS supply.

TL/F/5945-1 Hex COS/MOS to DTL or TTL converter (inverting).

Connect V_{CC} to DTL or TTL supply. Connect V_{DD} to COS/MOS supply.

TL/F/5945-3

Absolute Maximum Ratings

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/Distributors for availability and specifications.

Voltage at Any Pin (Note 1) $V_{SS} - 0.3V$ to $V_{SS} + 15.5V$ Operating Temperature Range CD40XXM -55°C to $+125^{\circ}\text{C}$

 Storage Temperature Range (Ts) $-65^{\circ}\text{C to } + 150^{\circ}\text{C}$

Power Dissipation (P_D)
Dual-In-Line 700 mW
Small Outline 500 mW

Lead Temperature (T_L)
(Soldering, 10 seconds)

Operating Range (V_{DD})

V_{SS} + 3V to V_{SS} + 15V

DC Electrical Characteristics

Symbol	Characteristics	Test Conditions (Volts)		Limits														
				CD40XXM						CD40XXC						Units		
				-55°C		+ 25°C			+ 125°C		-40°C		+ 25°C		;	+ 85°C		Ullits
		ν _o	V_{DD}	Min	Max	Min	Тур	Max	Min	Мах	Min	Max	Min	Тур	Мах	Min	Max	
ICC	Quiescent Device Current		5 10		0.3 0.5		0.01 0.01	0.3 0.5		20 30		3 5		0.03 0.05	- 1		42 70	μA μA
P _D	Quiescent Device Dissipation/Package		5 10		1.5 5		0.05 0.1	1.5 5		100 300		15 50		0.15 0.5	15 50		210 700	μW μW
V _{OL} V _{OH}	Output Voltage Low Level High Level		5 10 5 10		0.01 0.01	4.99 9.99	0 0 5 10	0.01 0.01		0.05 0.05	4.99 9.99	0.01 0.01	4.99 9.99	1 -	0.01 0.01	4.95 9.95	0.05 0.05	V V V
	Noise Immunity (All Inputs)																	
V_{NL}	CD4009M {	$\begin{array}{c} V_O \geq 4.0 \\ V_O \geq 8.0 \end{array}$	5 10	1 2		1 2	2.25 4.5		0.9 1.9		1 2		1 2	2.25 4.5		0.9 1.9		V V
V_{NL}	CD4010M {	$V_O \ge 1.5$ $V_O \ge 3.0$	5 10	1.6 3.2		1.5 3	2.25 4.5		1.4 2.9		1.6 3.2		1.5 3	2.25 4.5		1.4 2.9		V V
V _{NH}		$\begin{array}{c} V_O \geq 3.5 \\ V_O \geq 7.0 \end{array}$	5 10	1.4 2.9		1.5 3	2.25 4.5		1.5 3		1.4 2.9		1.5 3	2.25 4.5		1.5 3		V V
I _D N I _D P	Output Drive Current N-Channel (Note 2) P-Channel (Note 2)	0.4 0.5 2.5 9.5	5 10 5 10	3.75 10 -1.85 -0.9		3 8 -1.25 -0.6			2.1 5.6 -0.9 -0.4		3.6 9.6 -1.5 -0.72		3 8 -1.25 -0.6			2.4 6.4 -1 -0.48		mA mA mA
I _{IN}	Input Current						10							10				pA

Note 1: This device should not be connected to circuits with the power on because high transient voltage may cause permanent damage.

Note 2: I_DN and I_DP are tested one output at a time.

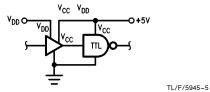
AC Electrical Characteristics*

 $T_A=25^{\circ}c,\,C_L=15$ pF, unless otherwise noted. Typical Temperature coefficient for all values of $V_{DD}=0.3\%/^{\circ}C$

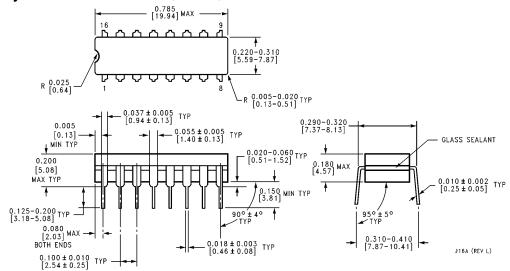
	Test								
Characteristics	Conditi		CD40XXI	Л		Units			
Ondiadoteristics		V _{DD} (Volts)	Min	Тур	Max	Min	Тур	Max	Omis
Propagation Delay Time: High-to-Low Level (t _{PHL})	$V_{CC} = V_{DD}$	5 10	_	15 10	55 30	_	15 10	70 40	
	$V_{DD} = 10V$ $V_{CC} = 5V$		_	10	25	_	10	35	ns
Low-to-High Level (t _{PLH})	$V_{CC} = V_{DD}$	5 10	_	50 25	80 55	<u>-</u>	50 25	100 70	
	$V_{DD} = 10V$ $V_{CC} = 5V$		_	15	30	_	15	40	ns
Transition Time: High-to-Low Level (t _{THL})	$V_{CC} = V_{DD}$	5 10	_ _	20 16	45 40	_	20 16	60 50	ns
Low-to-High Level (t _{TLH})	$V_{CC} = V_{DD}$	5 10	_ _	80 50	125 100	_ _	80 50	160 120	ns
Input Capacitance (C _I)	Any Input		-	5	-	_	5	_	pF

^{*}AC Parameters are guaranteed by DC correlated testing.

Typical Application



Physical Dimensions inches (millimeters)



Ceramic Dual-In-Line Package (J) Order Number CD4009MJ, CD4009CJ, CD4010MJ or CD4010CJ NS Package Number J16A

Physical Dimensions inches (millimeters) (Continued) 0.740 - 0.780 (18.80 - 19.81) (2.286) 16 15 14 13 12 11 10 INDEX AREA 0.250 ± 0.010 $\overline{(6.350 \pm 0.254)}$ PIN NO. 1 1 2 3 4 5 6 7 8 1 2 IDENT IDENT OPTION 01 OPTION 02 $\frac{0.065}{(1.651)}$ $\frac{0.130 \pm 0.005}{(3.302 \pm 0.127)}$ $\frac{0.060}{(1.524)}$ TYP $\frac{0.300 - 0.320}{(7.620 - 8.128)}$ 4° TYP OPTIONAL ¥ $\frac{0.145 - 0.200}{(3.683 - 5.080)}$ 95°±5° $\frac{0.008 - 0.016}{(0.203 - 0.406)}$ TYP 90°±4° TYP 0.020 MIN $\frac{0.280}{(7.112)}$ (0.508)0.125 **-** 0.150 (3.175 **-** 3.810) 0.030 ± 0.015 MIN (0.762 ± 0.381) 0.014 - 0.023 0.100 ± 0.010 (0.325 +0.040 -0.015 (0.356 = 0.584) TYP (2.540 **±** 0.254) TYP $\frac{0.050 \pm 0.010}{(1.270 \pm 0.254)}$ N16E (REV F) (8.255 **+**1.016)

Molded Dual-In-Line Package (N)
Order Number CD4009MN, CD4009CN, CD4010MN or CD4010CN
NS Package Number N16E

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- A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.



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